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Application/Control No.	Applicant(s)/Patent under Reexamination
09/520,405	MARTINEK ET AL.
Examiner	Art Unit
Aashish Karkhanis	3714

	SEARCHED		
Class	Subclass	Date	Examiner
364	140	6/26/2006	ARK
371	66	6/26/2006	ARK
395	680	6/26/2006	ARK

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH	DATE	EXMR
text search for process scheduling and UPS power supplies	6/26/2006	ARK
databases searched: USPAT, US- PGPUB,EPO,JPO,Derwent	6/26/2006	ARK
search updated	2/26/2007	ARK
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